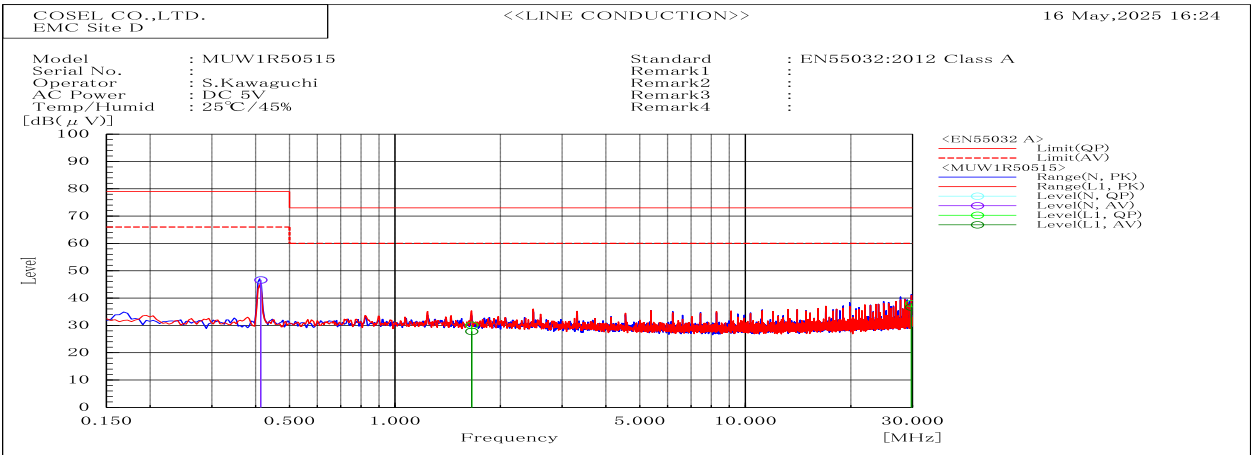
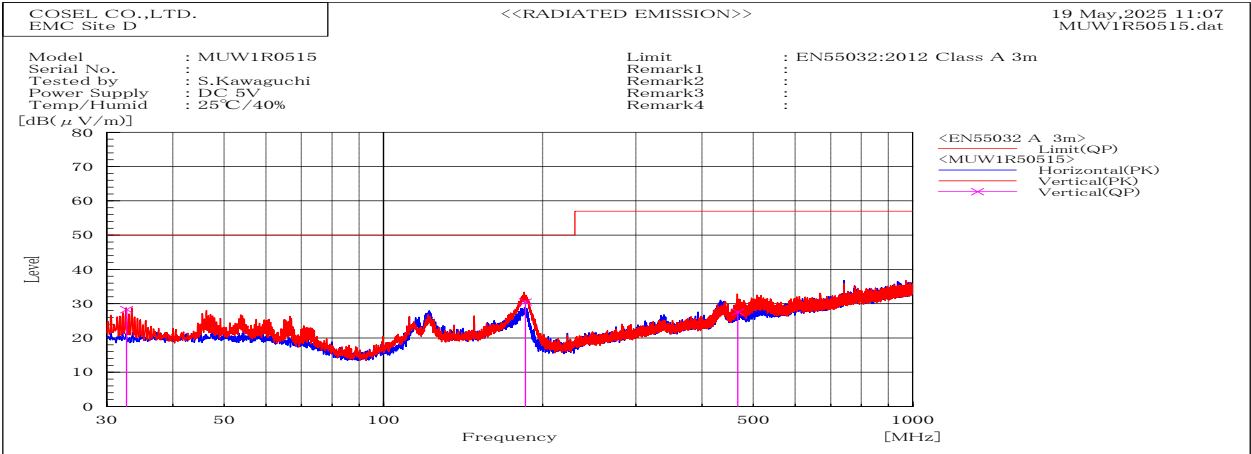


DATA SHEET		Date	19-May-25
Model	MUW1R50515	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



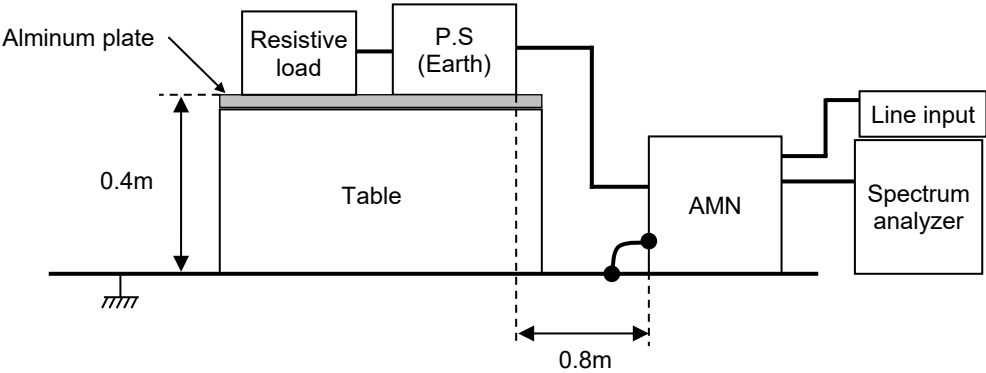
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
1.656	L1	30.1	27.8	73	60	42.9	32.2	Pass	
29.803	L1	38	36.7	73	60	35	23.3	Pass	
0.414	N	46.8	46.6	79	66	32.2	19.4	Pass	



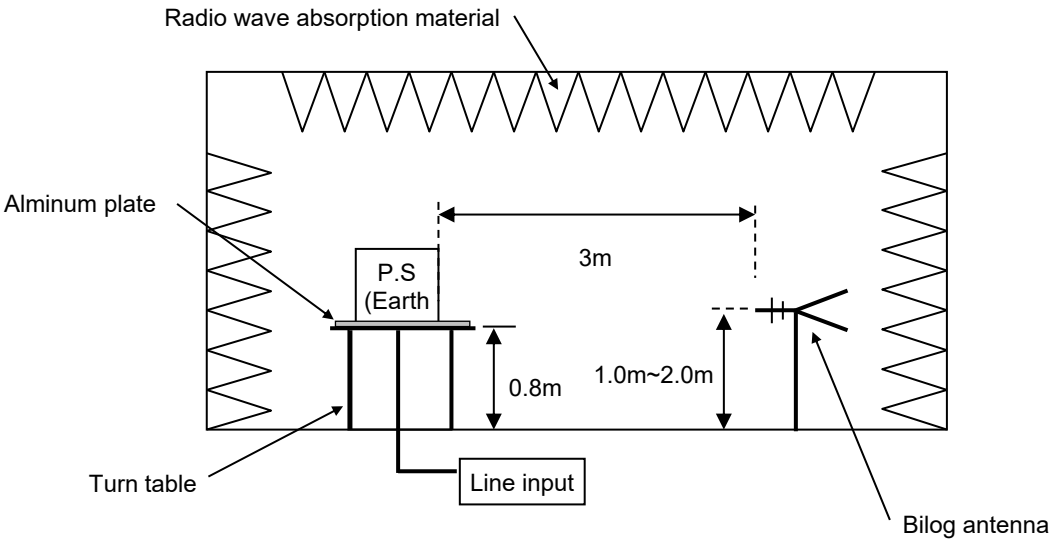
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
185.523	V	Stable	30.5	50	19.5	Pass	100.2	23.4	
32.704	V	Stable	28.3	50	21.7	Pass	100.2	169.1	
467.348	V	Stable	27.6	57	29.4	Pass	116.1	201.8	

DATA SHEET		Date	19-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

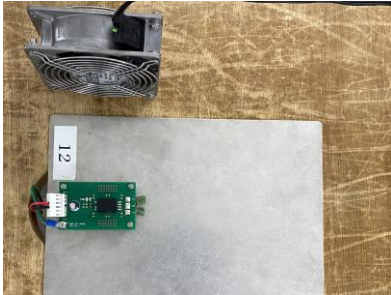
Test : EMI
Model Name: MUW1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

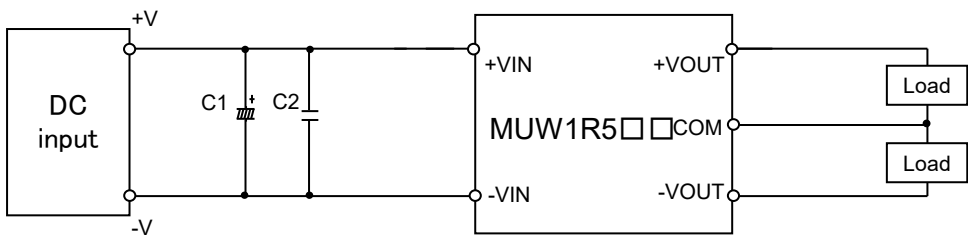


Fig.1 MUW1R505□, MUW1R512□, MUW1R524□ Testing circuitry

- C1 : MUW1R505□ 16V 220 μ F Electric capacitor (UPWseries NICHICON)
MUW1R512□ 50V 100 μ F Electric capacitor (UPWseries NICHICON)
MUW1R524□ -
- C2 : MUW1R505□ 16V 22 μ F Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
MUW1R512□ 25V 22 μ F Ceramic capacitor (C3216JB1E226MT TDK)
MUW1R524□ 50V 10 μ F Ceramic capacitor (C3216X7R1H106KT TDK)

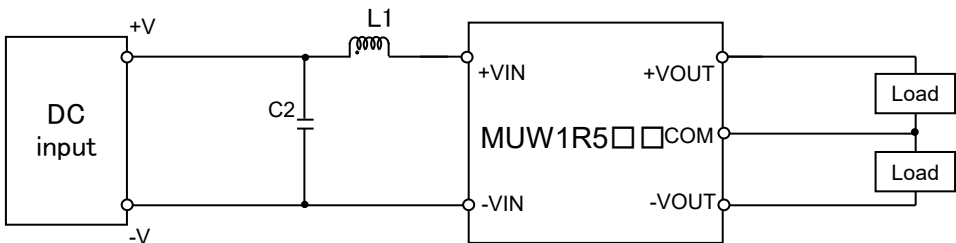


Fig.2 MUW1R548□ Testing circuitry

- C2 : MUW1R548□ 100V 2.2 μ F Ceramic capacitor (C3216X7S2A225KT TDK)
- L1 : MUW1R548□ 520mA 15 μ H Inductor (LQH32PN150MN0L MURATA MANUFACTURING)